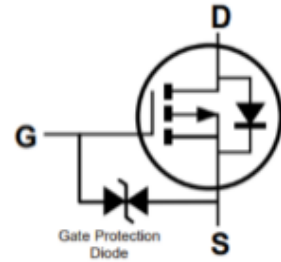


## Features

- Low on-resistance
- High-speed switching
- Drive circuits can be simple
- Parallel use is easy
- ESD protected gate up to 1kV HBM
- Halogen free
- Qualified to AEC-Q101 standards for high reliability

HF

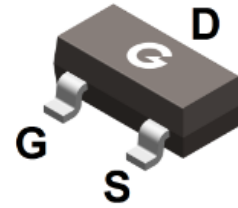


## Typical Applications

- P-channel enhancement mode effect transistor
- Switching application

## Mechanical Data

- Case: SOT-23
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208



SOT-23

## Ordering Information

| Part Number | Package | Shipping Quantity      | Marking Code |
|-------------|---------|------------------------|--------------|
| T2N7001K    | SOT-23  | 3000 pcs / Tape & Reel | 7001K        |

## Maximum Ratings (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

| Parameter                                                                 | Symbol    | Value      | Unit             |
|---------------------------------------------------------------------------|-----------|------------|------------------|
| Drain-Source Voltage                                                      | $V_{DS}$  | -60        | V                |
| Gate -Source Voltage                                                      | $V_{GS}$  | $\pm 20$   | V                |
| Continuous Drain Current ( $T_C = 25^\circ\text{C}$ )                     | $I_D$     | -0.3       | A                |
| Continuous Drain Current ( $T_A = 25^\circ\text{C}$ ) <sup>*1</sup>       |           | -0.2       | A                |
| Continuous Drain Current ( $T_A = 70^\circ\text{C}$ ) <sup>*1</sup>       |           | -0.16      | A                |
| Pulsed Drain Current ( $t_p = 10\mu\text{s}$ , $T_A = 25^\circ\text{C}$ ) | $I_{DM}$  | -1         | A                |
| Single Pulse Avalanche Energy <sup>*3</sup>                               | $E_{AS}$  | 0.3        | mJ               |
| Power Dissipation ( $T_A = 25^\circ\text{C}$ ) <sup>*1</sup>              | $P_D$     | 0.36       | W                |
| Operating Junction Temperature Range                                      | $T_J$     | -55 ~ +150 | $^\circ\text{C}$ |
| Storage Temperature Range                                                 | $T_{STG}$ | -55 ~ +150 | $^\circ\text{C}$ |

### Thermal Characteristics

| Parameter                                         | Symbol           | Min. | Typ. | Max. | Unit |
|---------------------------------------------------|------------------|------|------|------|------|
| Thermal Resistance Junction-to-Air <sup>*1</sup>  | R <sub>θJA</sub> | -    | 330  | 347  | °C/W |
| Thermal Resistance Junction-to-Case <sup>*1</sup> | R <sub>θJC</sub> | -    | 185  | 208  | °C/W |
| Thermal Resistance Junction-to-Lead <sup>*1</sup> | R <sub>θJL</sub> | -    | 145  | 175  | °C/W |

### Electrical Characteristics (@ T<sub>A</sub> = 25°C unless otherwise specified)

| Symbol                             | Parameter                       | Test Condition                                                            | Min. | Typ.  | Max. | Unit |
|------------------------------------|---------------------------------|---------------------------------------------------------------------------|------|-------|------|------|
| Static Characteristics             |                                 |                                                                           |      |       |      |      |
| V <sub>DSS</sub>                   | Drain-Source Breakdown Voltage  | V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA                             | -60  | -     | -    | V    |
| I <sub>DSS</sub>                   | Zero Gate Voltage Drain Current | V <sub>DS</sub> = -60V, V <sub>GS</sub> = 0V                              | -    | -     | -1   | μA   |
| I <sub>GSS</sub>                   | Gate-Body Leakage Current       | V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V                              | -    | -     | ±10  | μA   |
| On Characteristics                 |                                 |                                                                           |      |       |      |      |
| R <sub>DS(ON)</sub>                | Drain-Source On-resistance *2   | V <sub>GS</sub> = -10V, I <sub>D</sub> = -0.1A                            | -    | 1.8   | 4    | Ω    |
|                                    |                                 | V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -0.1A                           | -    | 2.3   | 5    |      |
| V <sub>GS(TH)</sub>                | Gate Threshold Voltage          | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA               | -1   | -1.5  | -2   | V    |
| Dynamic Characteristics            |                                 |                                                                           |      |       |      |      |
| g <sub>fs</sub>                    | Transconductance                | V <sub>DS</sub> = -10V, I <sub>D</sub> = -0.2A                            | -    | 0.5   | -    | S    |
| C <sub>ISS</sub>                   | Input Capacitance               | V <sub>GS</sub> = 0V                                                      | -    | 39    | -    | pF   |
| C <sub>OSS</sub>                   | Output Capacitance              | V <sub>DS</sub> = -20V                                                    | -    | 12    | -    |      |
| C <sub>RSS</sub>                   | Reverse Transfer Capacitance    | f = 1.0MHz                                                                | -    | 2     | -    |      |
| Switching Characteristics          |                                 |                                                                           |      |       |      |      |
| t <sub>d(ON)</sub>                 | Turn-on Delay Time *4           | V <sub>DS</sub> = -15V<br>R <sub>L</sub> = -50Ω<br>I <sub>D</sub> = -2.5A | -    | 2.5   | -    | ns   |
| t <sub>r</sub>                     | Turn-on Rise Time *4            |                                                                           | -    | 1     | -    |      |
| t <sub>d(OFF)</sub>                | Turn-Off Delay Time *4          |                                                                           | -    | 16    | -    |      |
| t <sub>f</sub>                     | Turn-Off Fall Time *4           |                                                                           | -    | 8     | -    |      |
| Q <sub>G</sub>                     | Total Gate-Charge               | V <sub>DS</sub> = -25V                                                    | -    | 2     | -    | nC   |
| Q <sub>GS</sub>                    | Gate to Source Charge           | V <sub>GS</sub> = -4.5V                                                   | -    | 0.7   | -    |      |
| Q <sub>GD</sub>                    | Gate to Drain (Miller) Charge   | I <sub>D</sub> = -0.2A                                                    | -    | 0.5   | -    |      |
| Source-Drain Diode Characteristics |                                 |                                                                           |      |       |      |      |
| V <sub>SD</sub>                    | Diode Forward Voltage *2        | I <sub>S</sub> = -0.2A, V <sub>GS</sub> = 0 V                             | -    | -0.87 | -1.4 | V    |

Notes:

1. The data tested by surface mounted on a minimum recommended pad
2. The data tested by pulsed, pulse width ≤ 300μs, duty cycle ≤ 2%
3. The E<sub>AS</sub> data shows Max. rating. The test condition is V<sub>DD</sub> = -30V, V<sub>GS</sub> = -10V, L = 0.1mH
4. Guaranteed by design, not subject to production

Ratings and Characteristics Curves (@  $T_A = 25^\circ\text{C}$  unless otherwise specified)

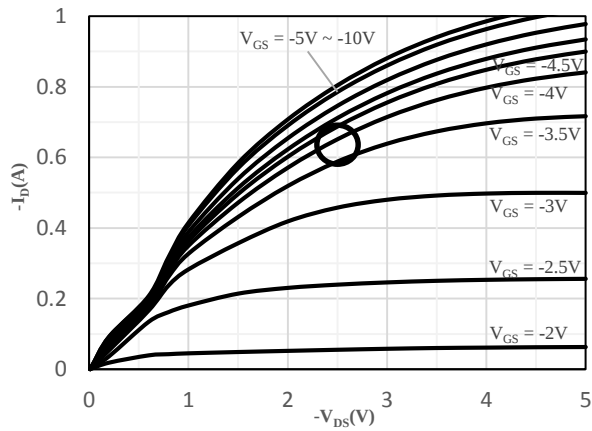


Fig 1 Typical Output Characteristics

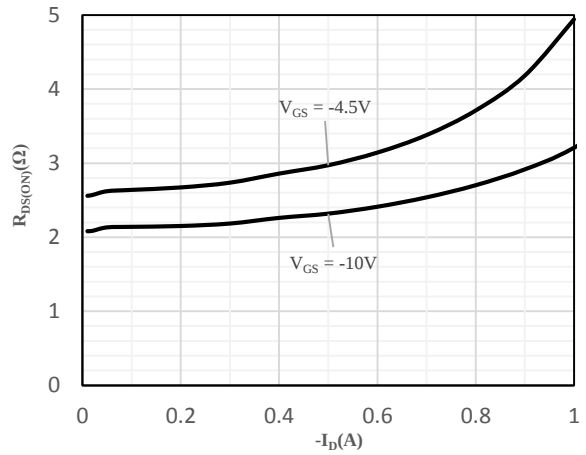


Fig 2 On-Resistance vs. Drain Current  
and Gate Voltage

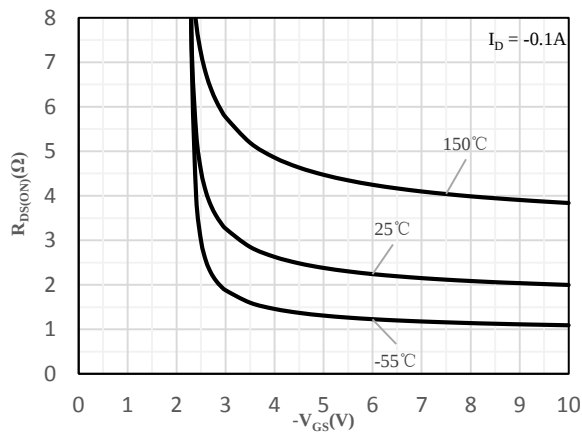


Fig 3 On-Resistance vs. Gate-Source Voltage

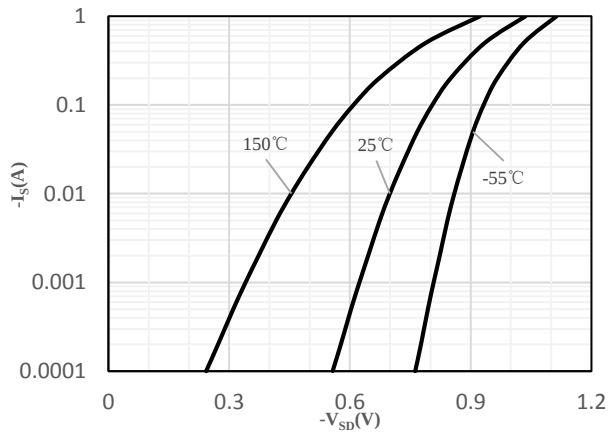


Fig 4 Body-Diode Characteristics

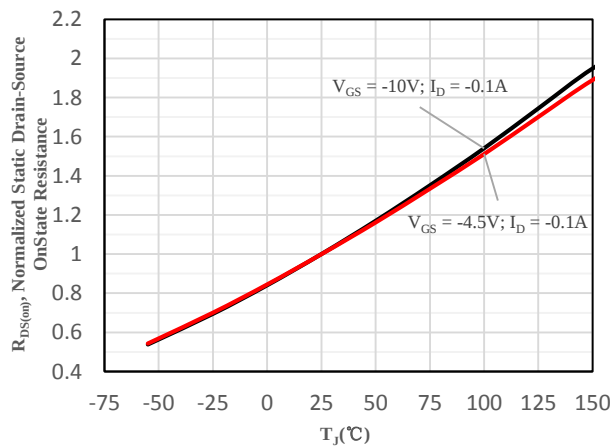


Fig 5 Normalized On-Resistance vs. Junction  
Temperature

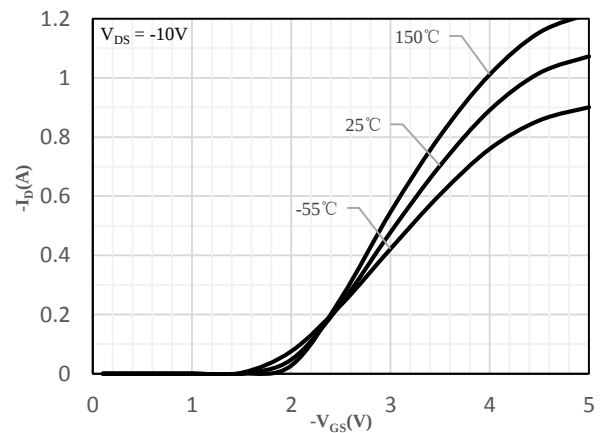


Fig 6 Transfer Characteristics

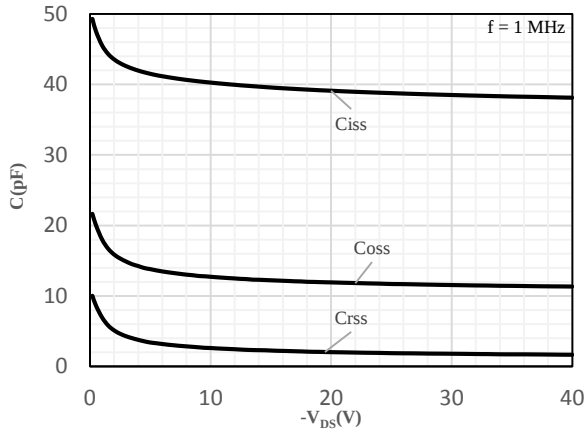


Fig 7 Capacitance Characteristics

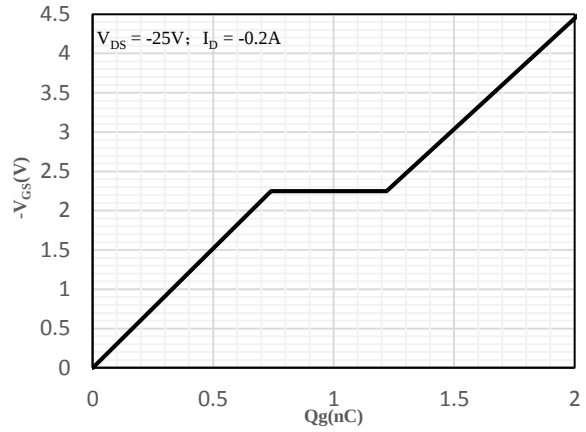


Fig 8 Gate-Charge Characteristics

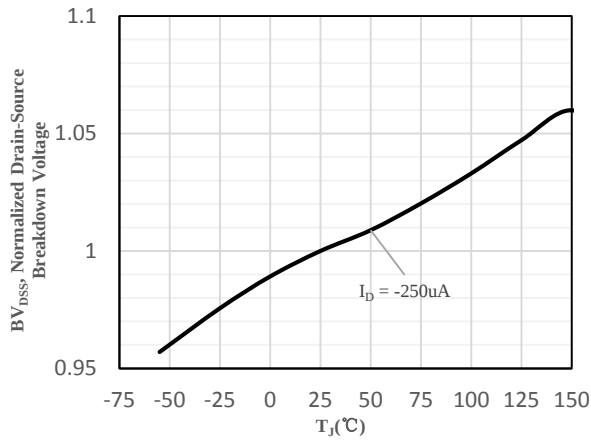


Fig 9 Normalized Breakdown Voltage  
vs. Junction Temperature

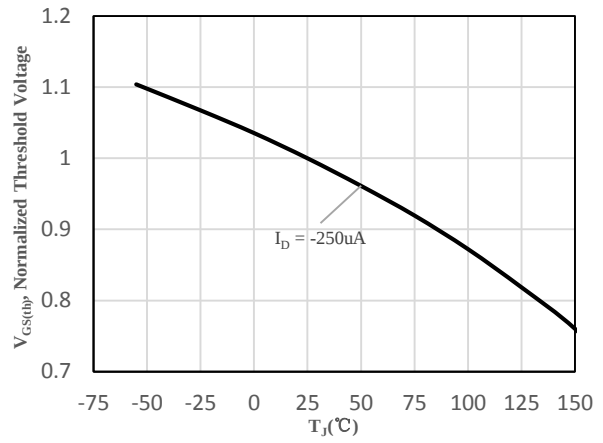


Fig 10 Normalized  $V_{GS(th)}$  vs. Junction Temperature

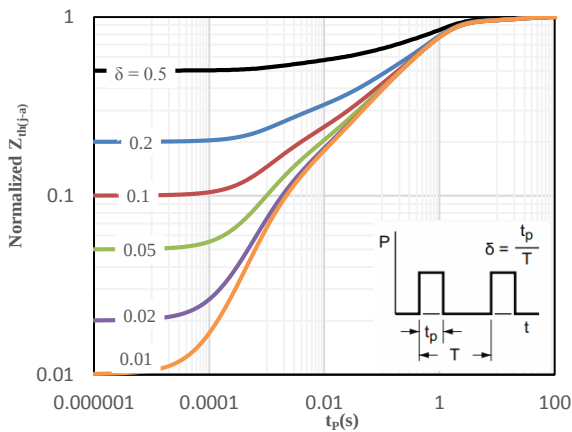
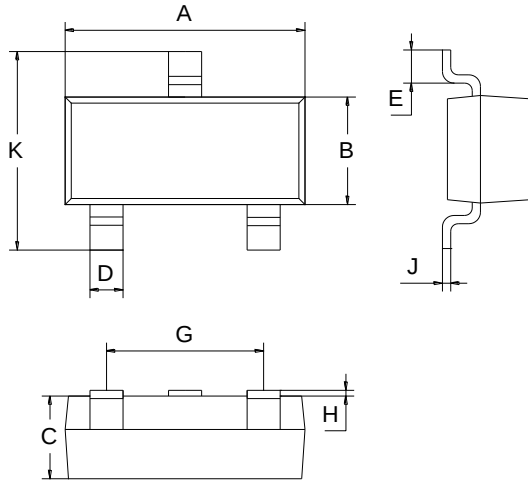


Fig 11 Normalized Maximum transient thermal  
impedance

**Package Outline Dimensions** (Unit: mm)

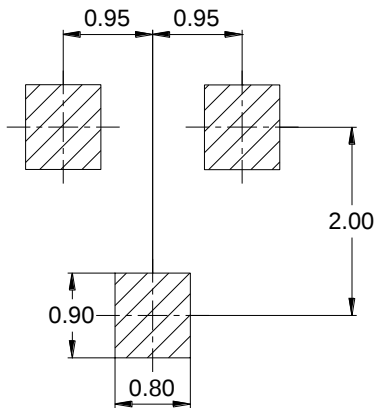
**SOT-23**



| SOT-23    |      |      |
|-----------|------|------|
| Dimension | Min. | Max. |
| A         | 2.70 | 3.10 |
| B         | 1.10 | 1.50 |
| C         | 0.90 | 1.10 |
| D         | 0.30 | 0.50 |
| E         | 0.35 | 0.48 |
| G         | 1.80 | 2.00 |
| H         | 0.02 | 0.10 |
| J         | 0.05 | 0.15 |
| K         | 2.20 | 2.60 |

**Mounting Pad Layout** (Unit: mm)

**SOT-23**



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